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Magnetic characterization of coated conductors

M. Eisterer

Atominstitut, Vienna University of Technology
Stadionallee 2, 1020 Vienna, Austria



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Outline

- Motivation
- Low temperature, in-field high resolution scans: magnetic granularity
- Calculation of the local currents from magnetic field maps: Inversion
 - Reel-to-reel mapping as a quality control tool
 - Tapes on magnetic substrates



Acknowledgments



Mayraluna Lao

Collaborations: IFW Dresden, Oxolutia, THEVA



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Motivation

Transport measurements:

- + Direct assessment of I_c
- High currents may be problematic (sample heating...)
- High electric field
- No information about limitations, inhomogeneities...

Scanning Hall probe measurements:

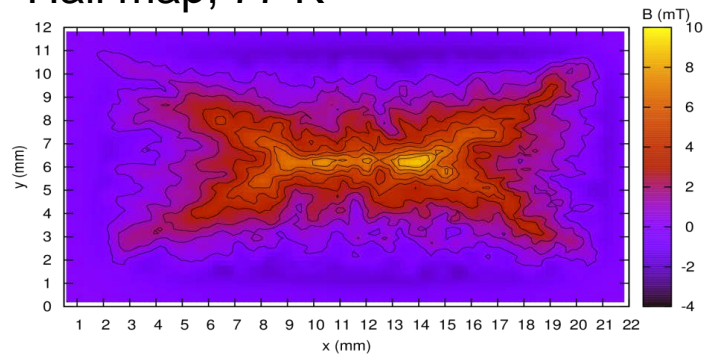
- + Assessment of inhomogeneities
- + Small electric field
- + Easy sample handling
- + No sample heating
- Modelling necessary to obtain I_c
- Slow



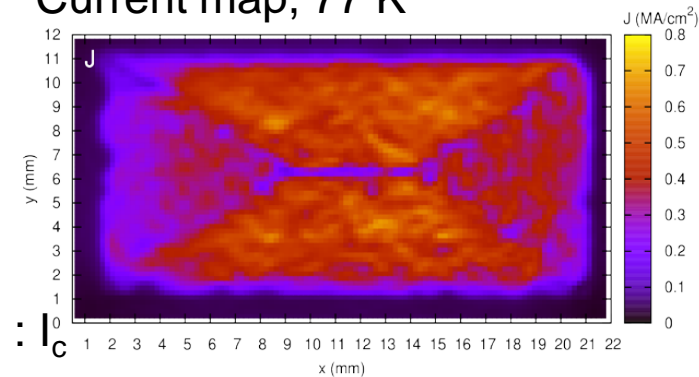
Example: critical current anisotropy



Hall map, 77 K



Current map, 77 K



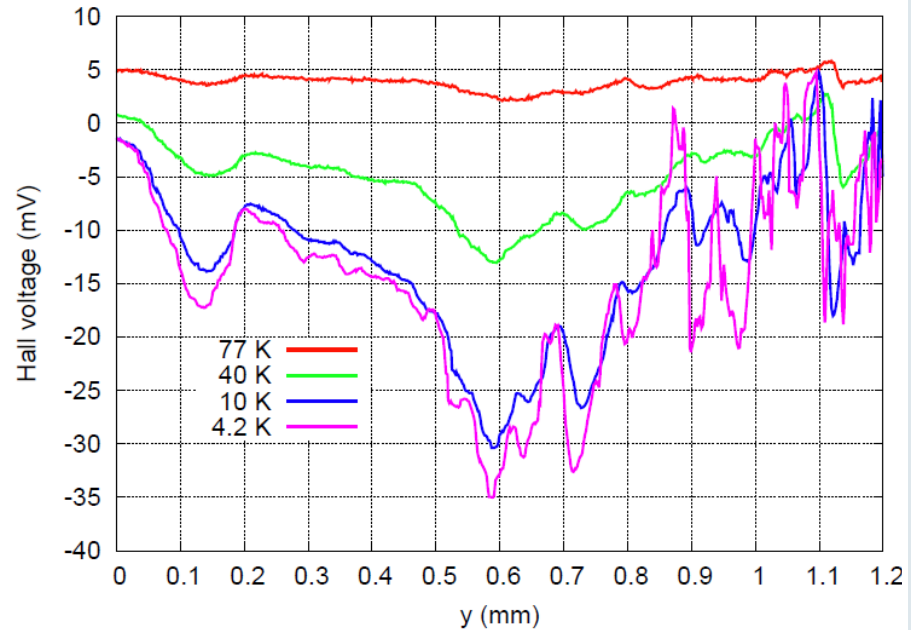
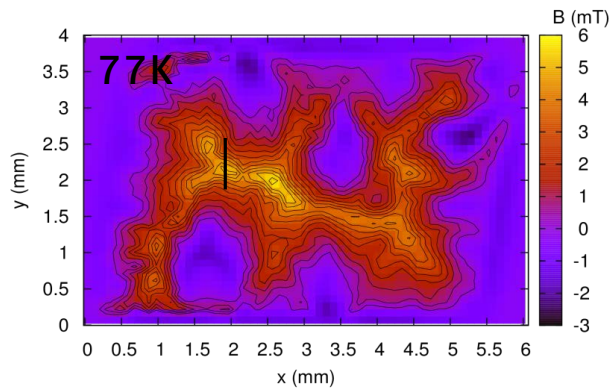
- Magnetic granularity
- J_c – anisotropy resulting from the aspect ratio of the grains
 - 64% Larger longitudinal current than transverse current.
 - Longitudinal → larger grain dimension
 - Transversal → smaller grain dimension



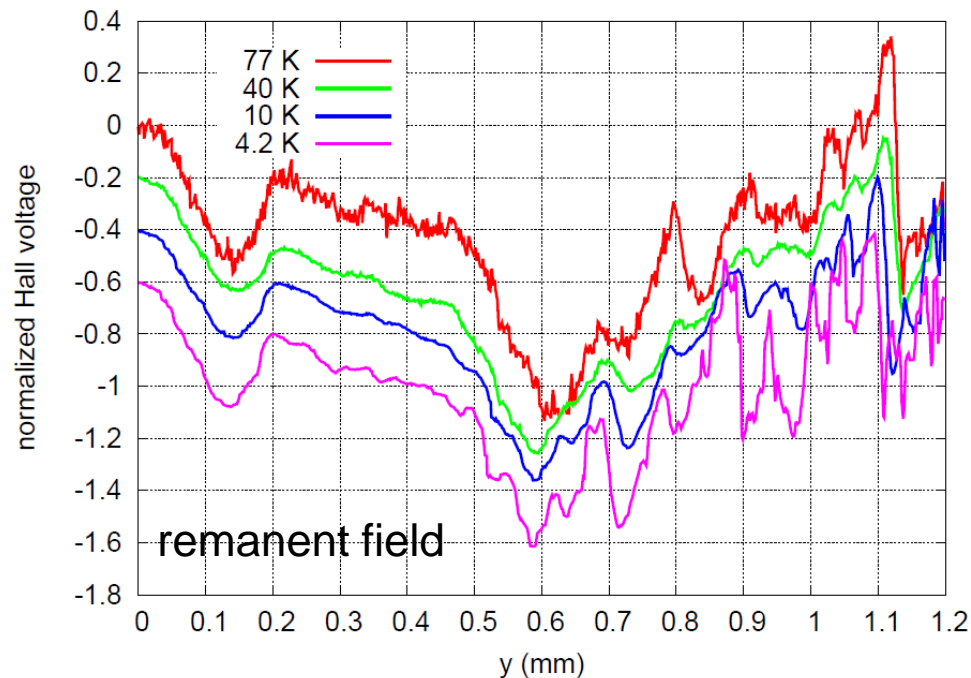
High resolution, low temperature scans



Line scans: 2 μm stepwidth, 2 μm hallprobe-surface distance



Temperature dependence of granularity



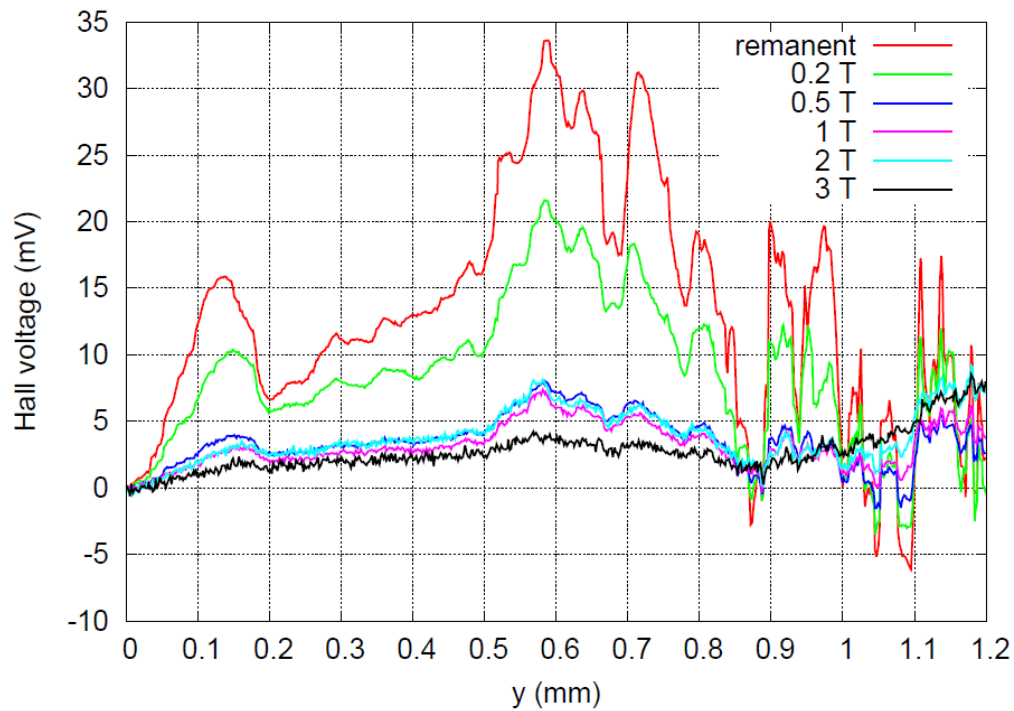
Peaks in the remnant field profile change with temperature.
→ Size of clusters of well connected superconducting grains changes.



Field dependence of granularity



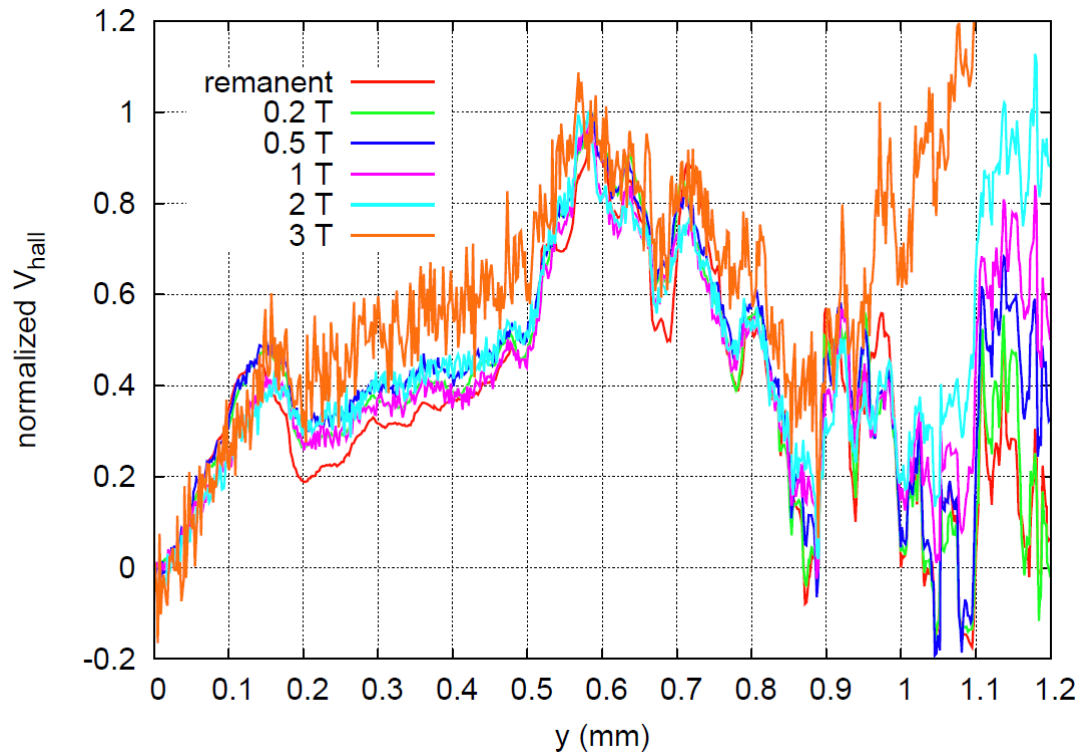
4.2 K



Field dependence of granularity



4.2 K



Calculation of the local current density from Hall maps

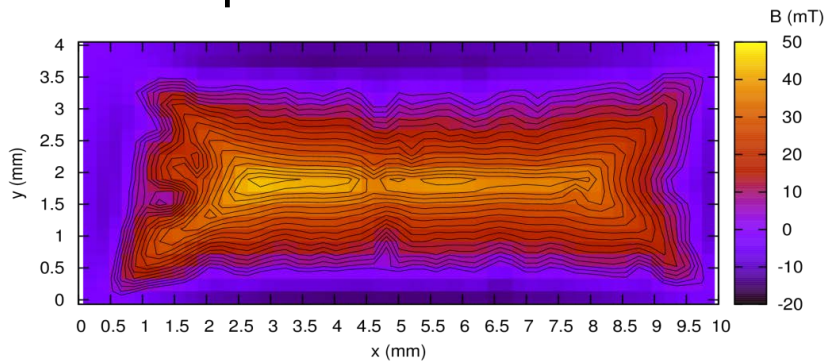
INVERSION



Influence of geometry

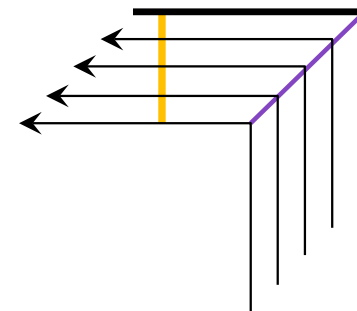
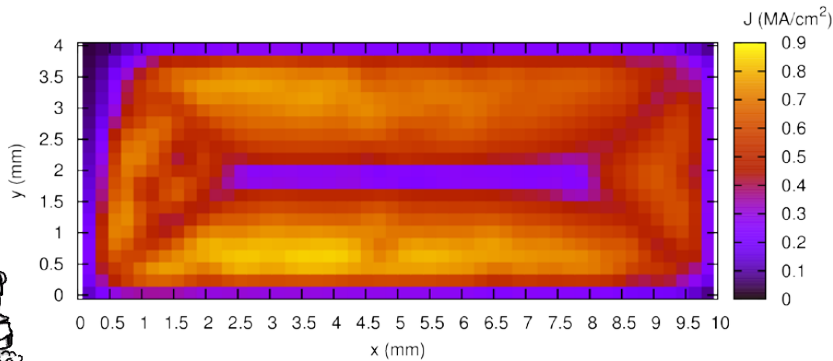


Hall map



- Lower currents at the peak of the field profile (artefact?)
- Lower currents at the diagonals near the edges (expected)

Current map

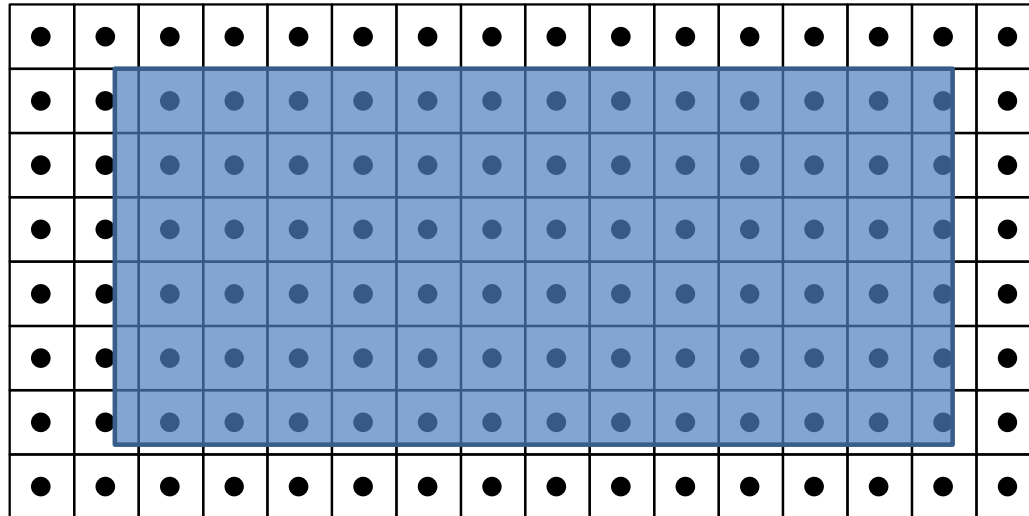


$$J_{\text{par}} = \sqrt{2} J_{\text{dia}}$$



Inversion of field maps

- Measurement grid  Current loop  Sample



$$B_i = M_{i,j} I_j$$
$$B = MI$$

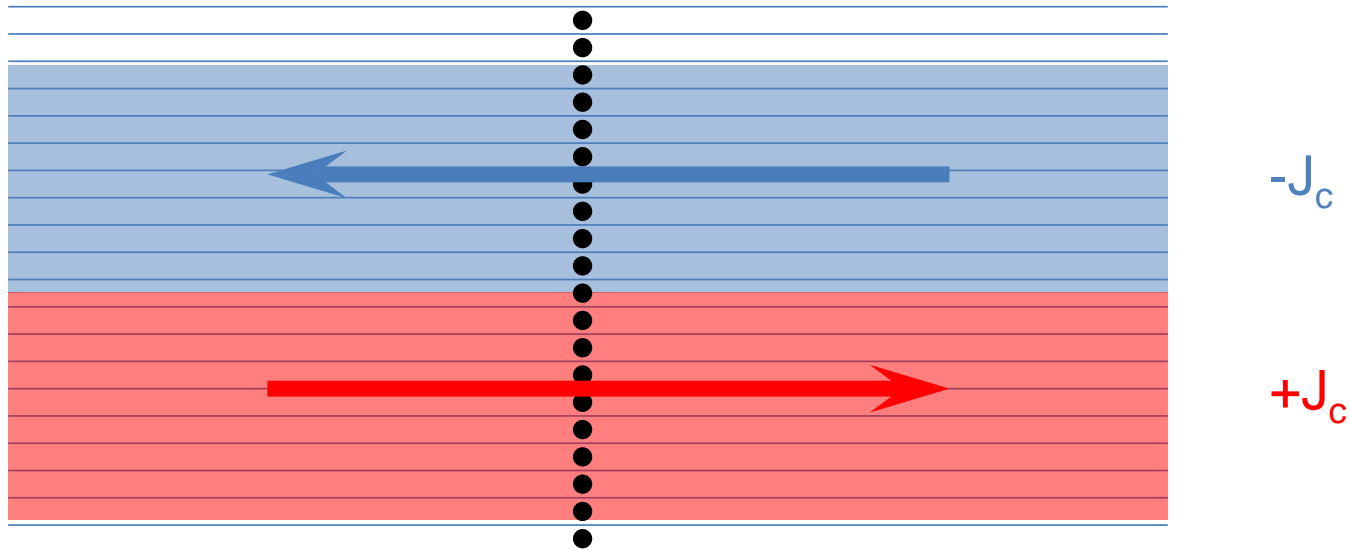
- Current grid in general does not fit the sample geometry!
- Calculated current is an ‘integral’ over the current density between to measurement point.
- Fine grid is favorable.



1D simplification

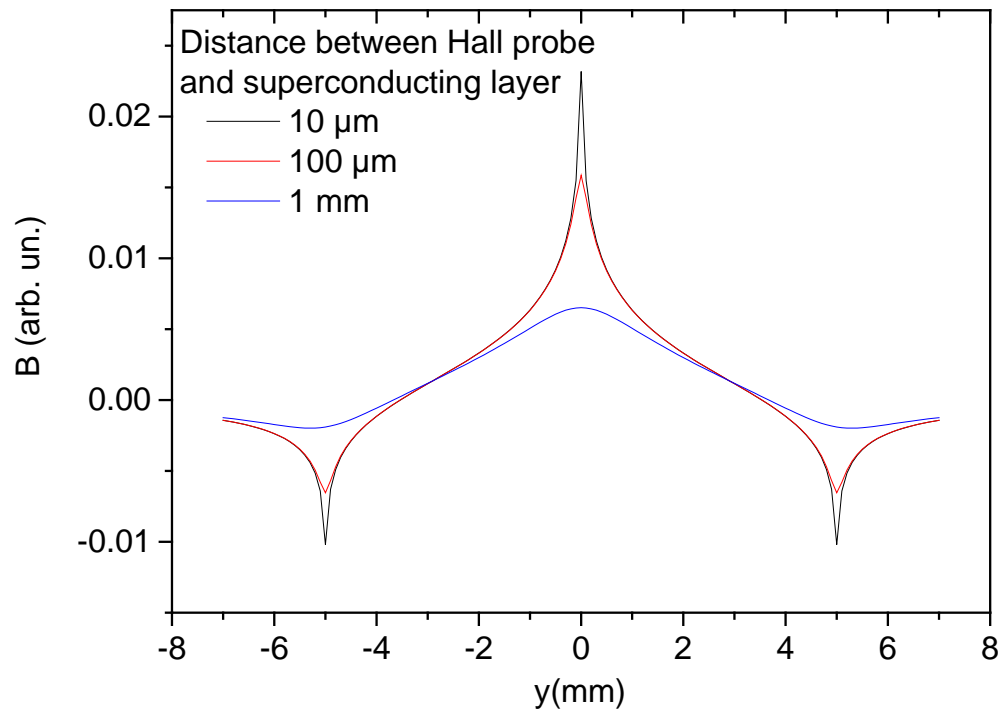
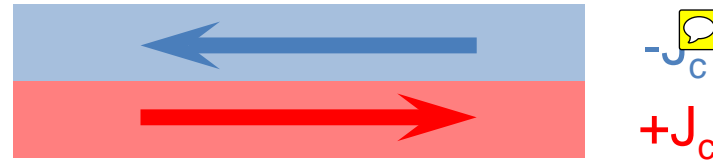


1 cm wide conductor, 0.6 mm measurement grid, 100 μm gap



Inversion of ideal field profile.

Ideal field profile



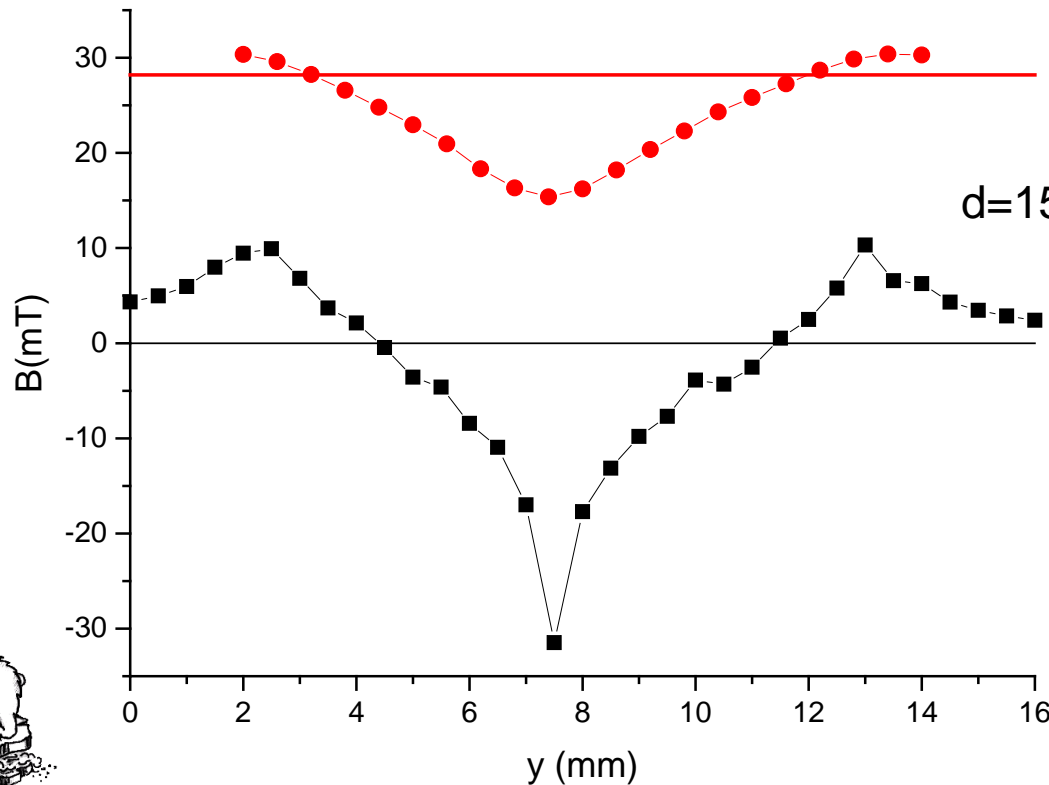
Smaller gap is favorable.



Transverse field profile at a homogeneous position



$d=850 \mu\text{m}$, $B_{\text{bg}}=28.2 \text{ mT}$



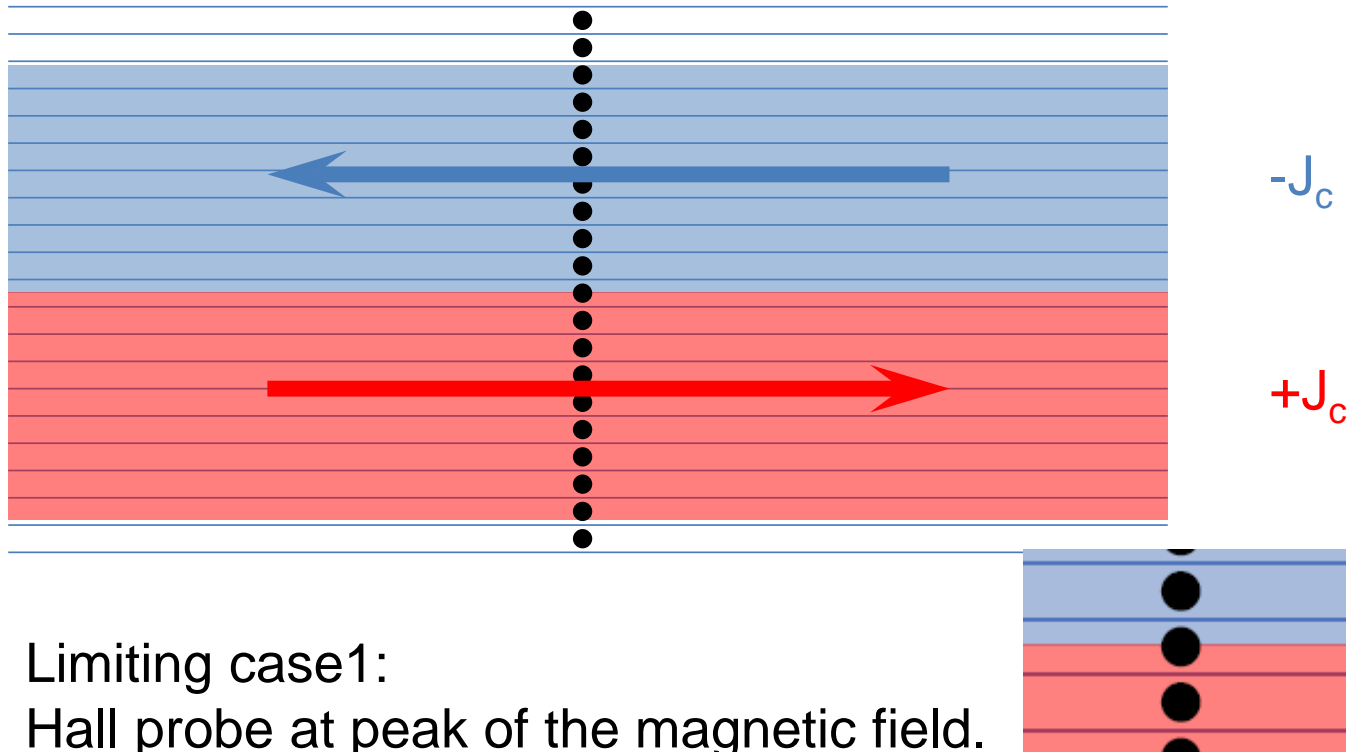
$d=15 \mu\text{m}$, $B_{\text{bg}} = 0 \text{ T}$



1D simplification

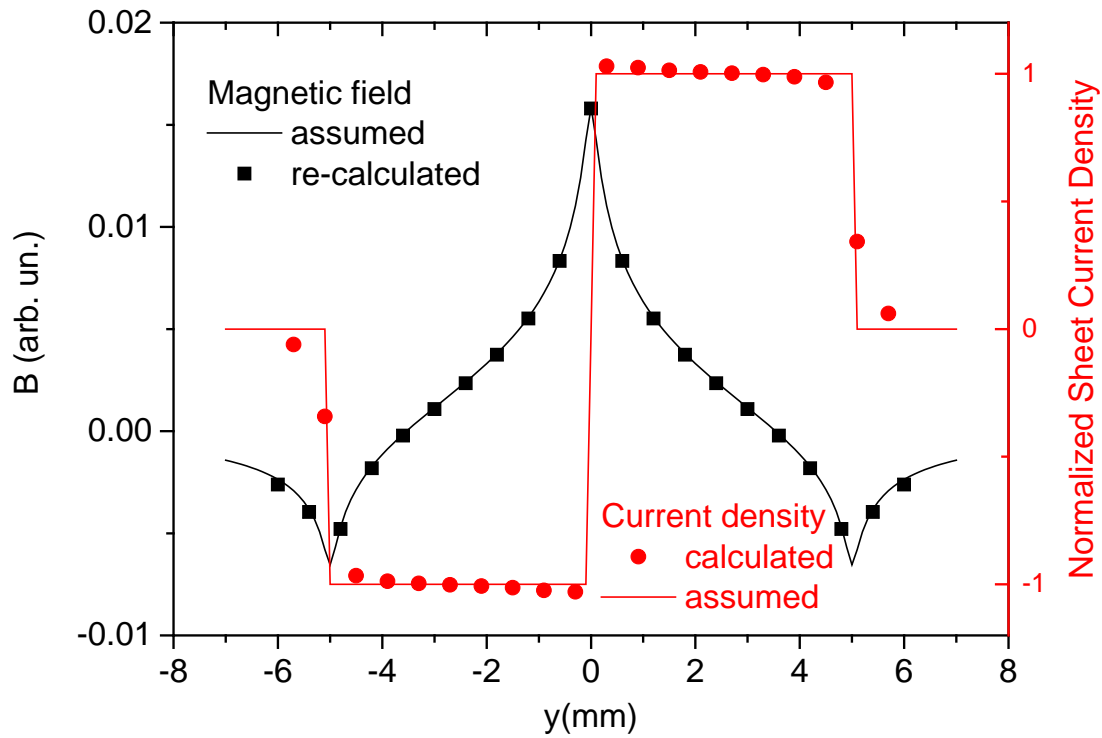


1 cm wide conductor, 0.6 mm measurement grid, 100 μm gap



Limiting case1:
Hall probe at peak of the magnetic field.

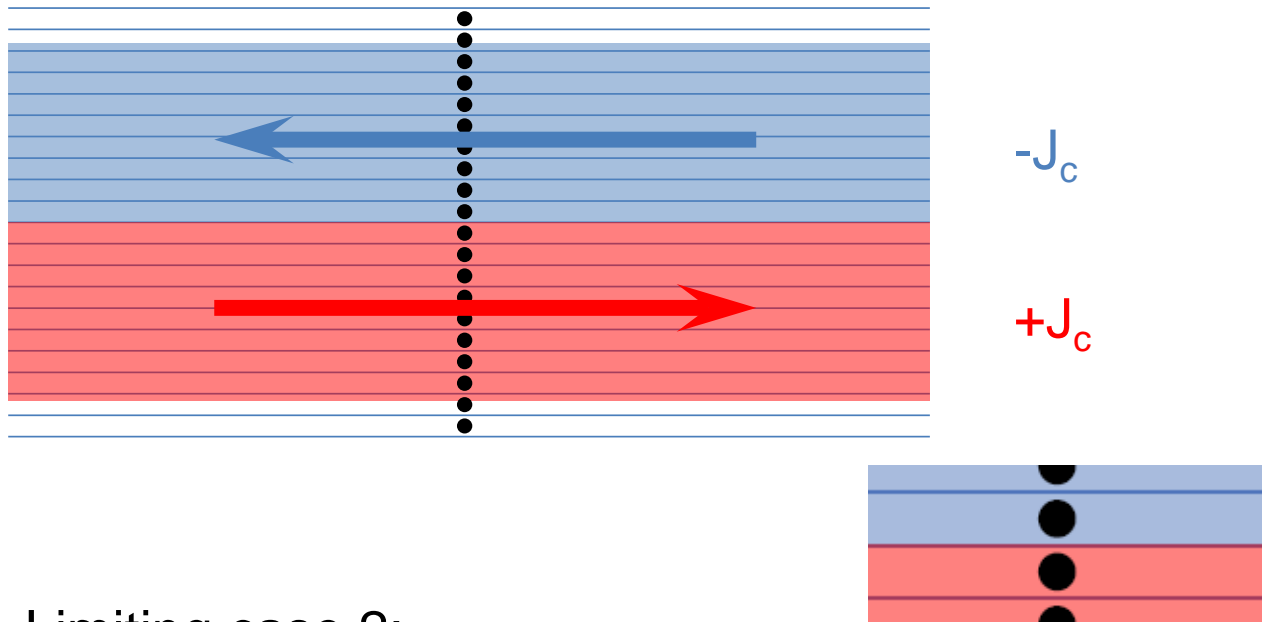
Limiting case: central Hall probe



1D simplification



1 cm wide conductor, 0.6 mm measurement grid, 100 μm gap



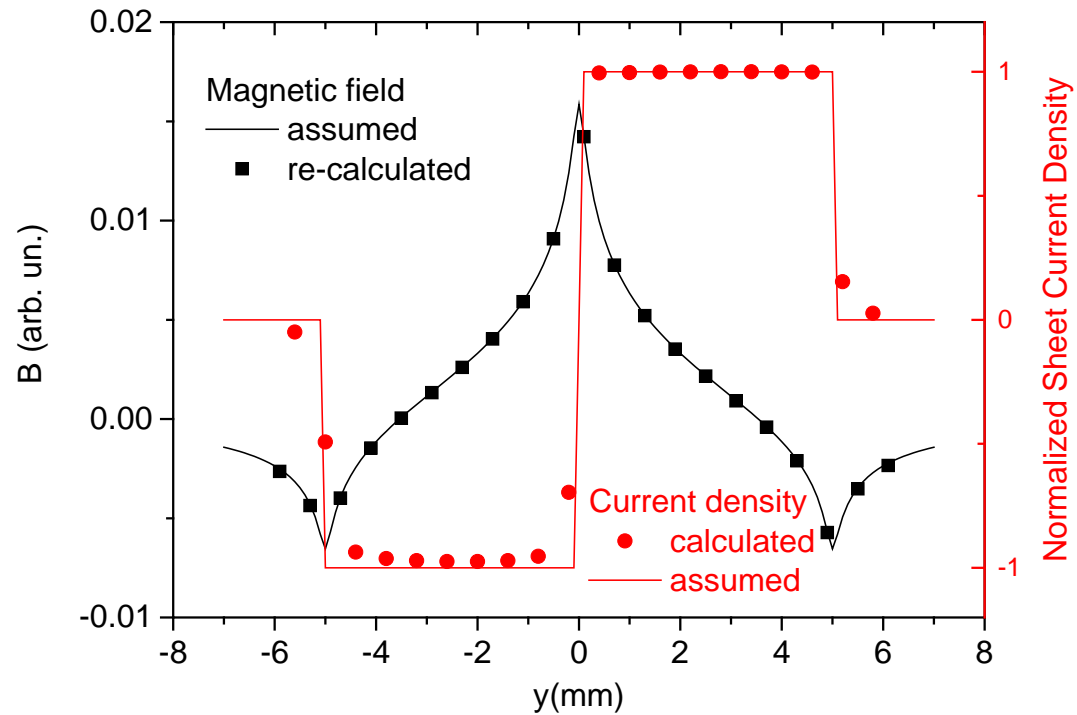
Limiting case 2:

Peak of the magnetic field between two Hall Probes.

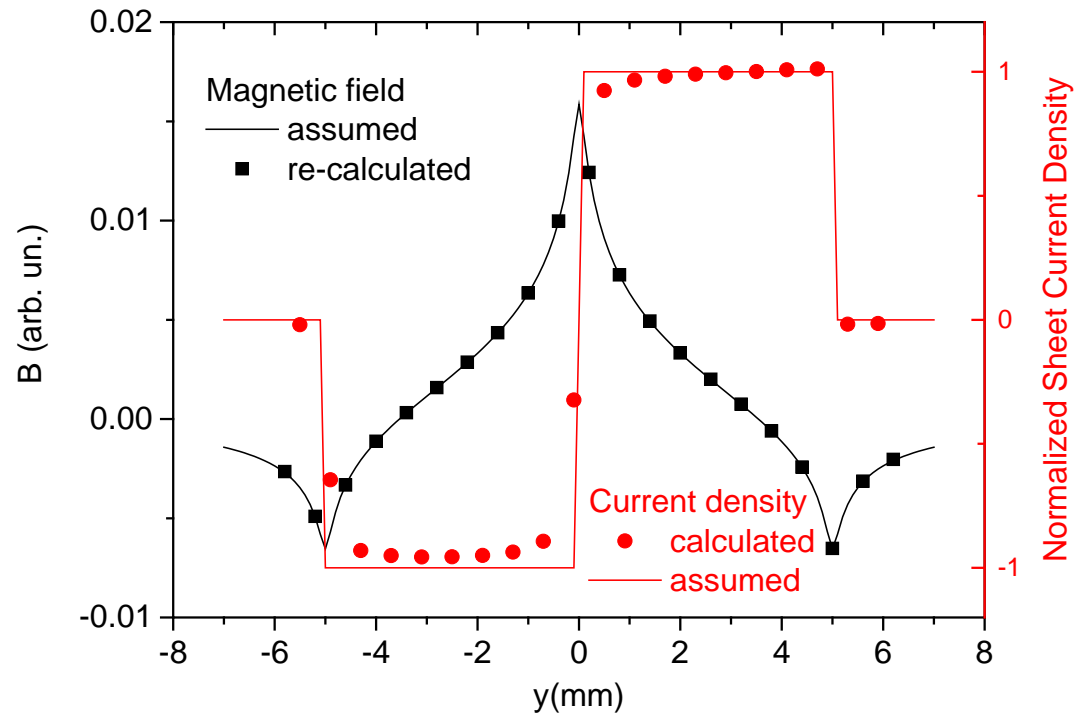
$\Delta y = 300 \mu\text{m}$.



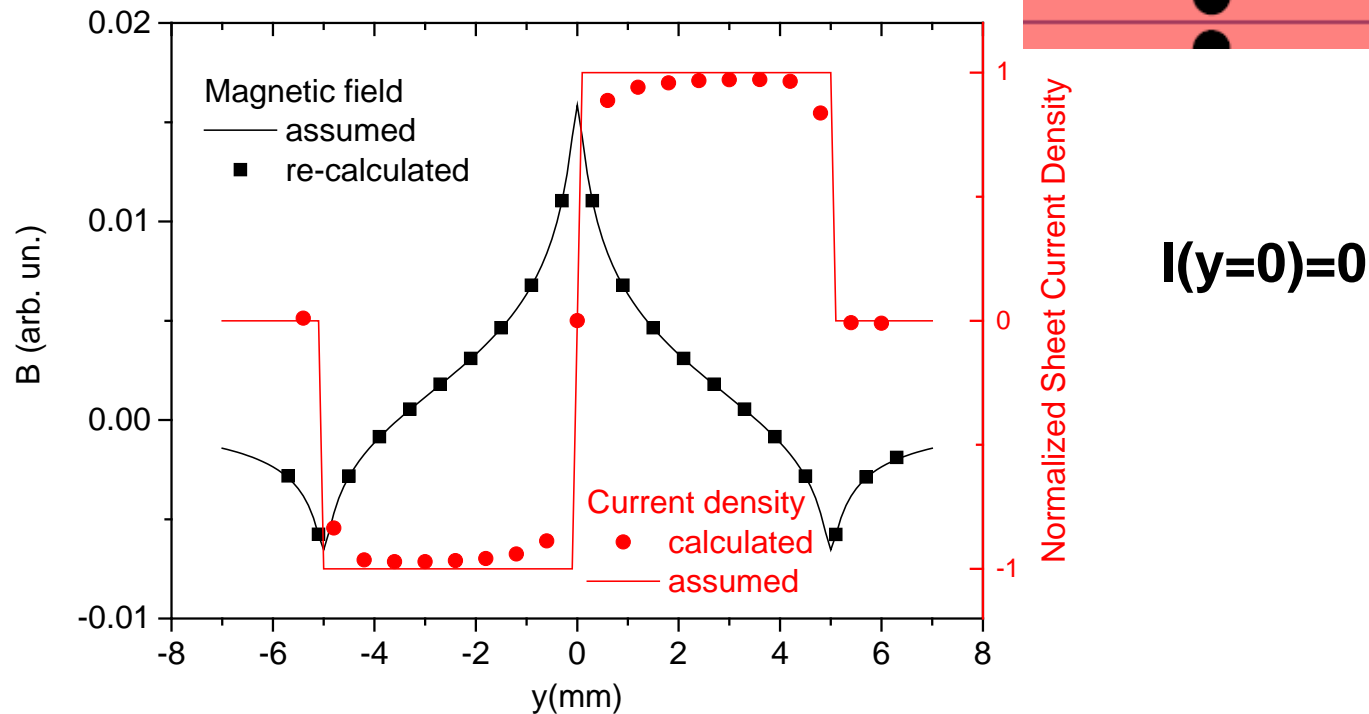
$\Delta y = 100 \mu\text{m}$



$\Delta y = 200 \mu\text{m}$



Limiting case 2: $\Delta y = 300 \mu\text{m}$



The calculated current $I = \sum_k I_k$ decreased from 101% of $I^{as} = \int J dF$ (case 1) to 90 % for case 2.

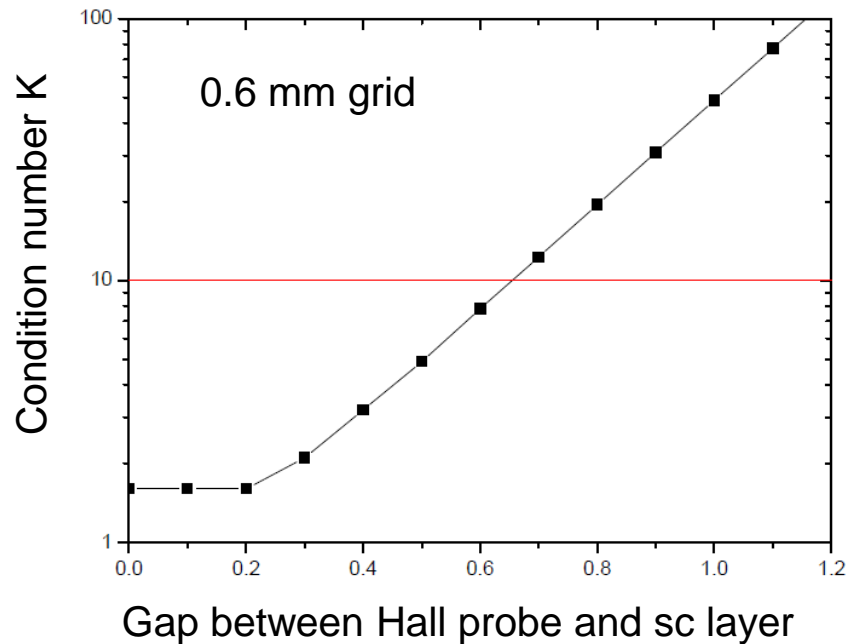
Larger gap between Hall probe and superconducting layer: 1mm

1 cm wide conductor, 1 mm measurement grid, 1mm gap

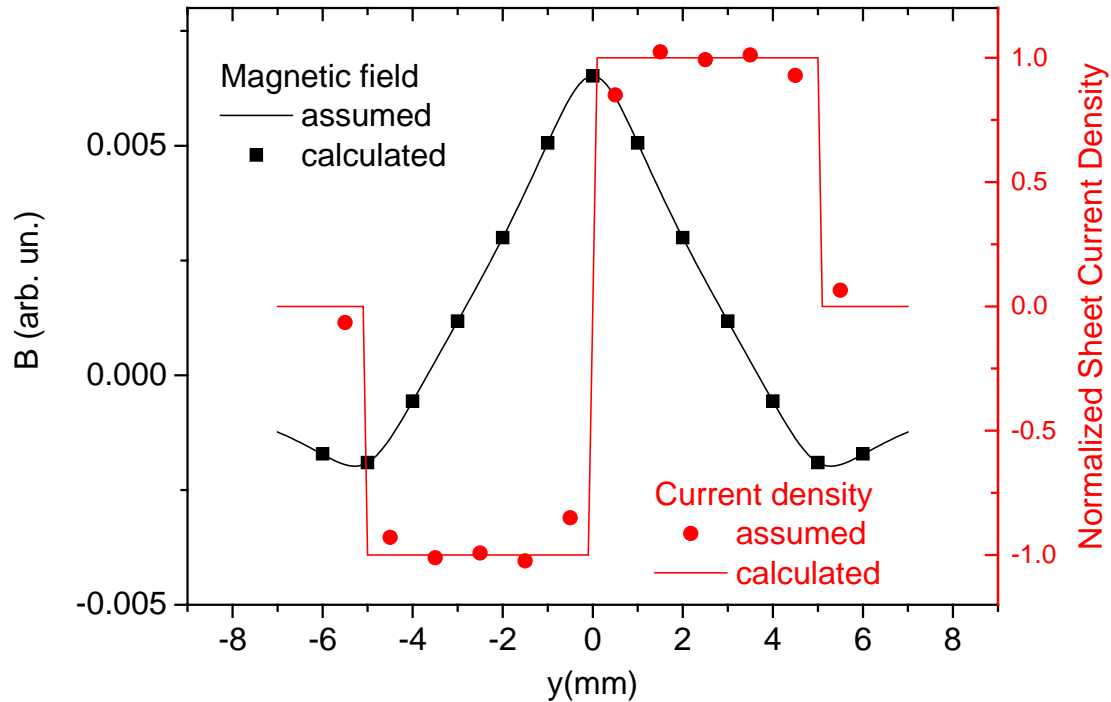
The current grid should not be smaller than the gap.



$$\Delta I \leq K \Delta B$$



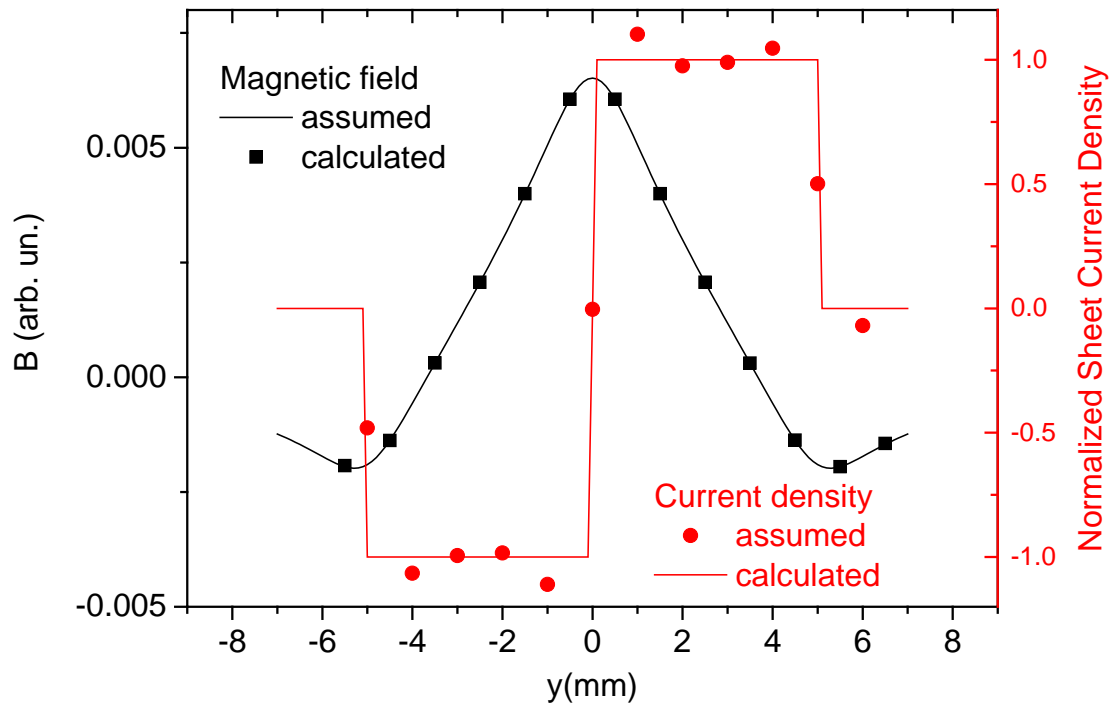
Gap 1 mm, case 1



Larger data scattering



Gap 1 mm, case 2



Few significant points, current is lower by 8%



REEL TO REEL MAPPING AS A QUALITY CONTROL TOOL



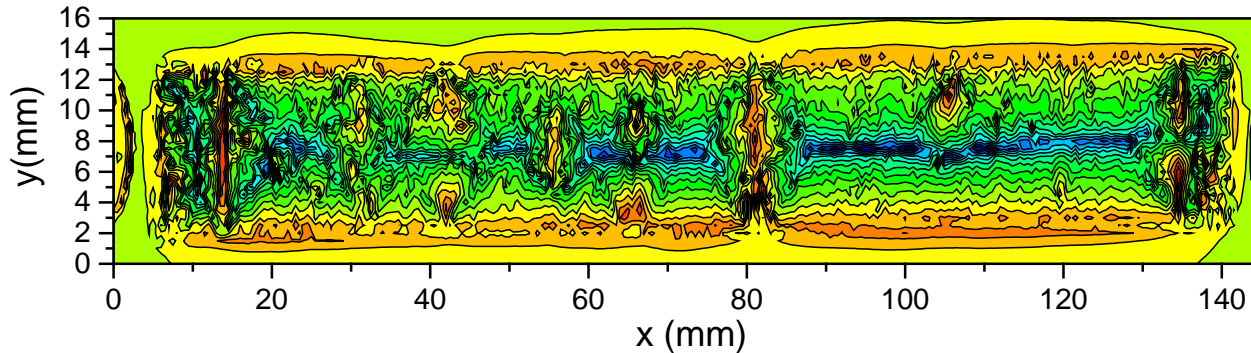
Hall scan 0.5x0.5 mm²

Distance Hall probe – superconducting layer: **15 μm**

REAL field profile



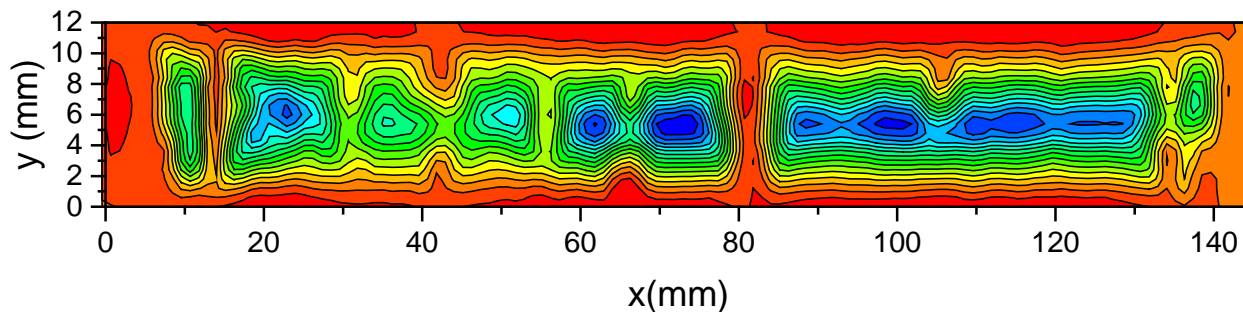
Local magnetic field



Reel-to-reel: 1.1x0.6 mm²

Distance Hall probe – superconducting layer: **850 μm**

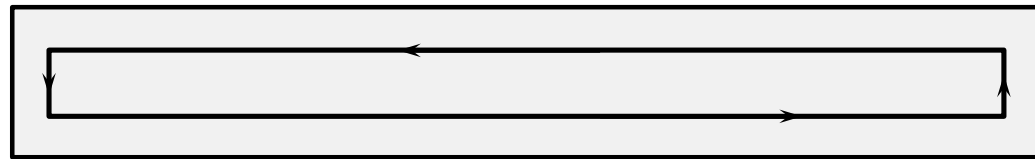
CONSTRUCTED field profile



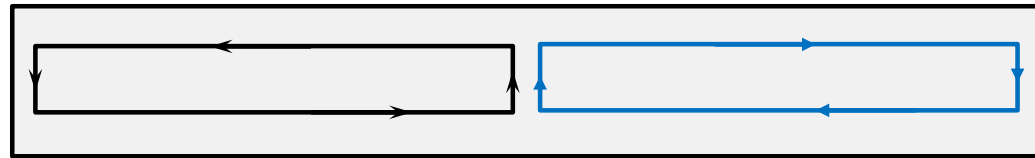


Induced currents

Hall map



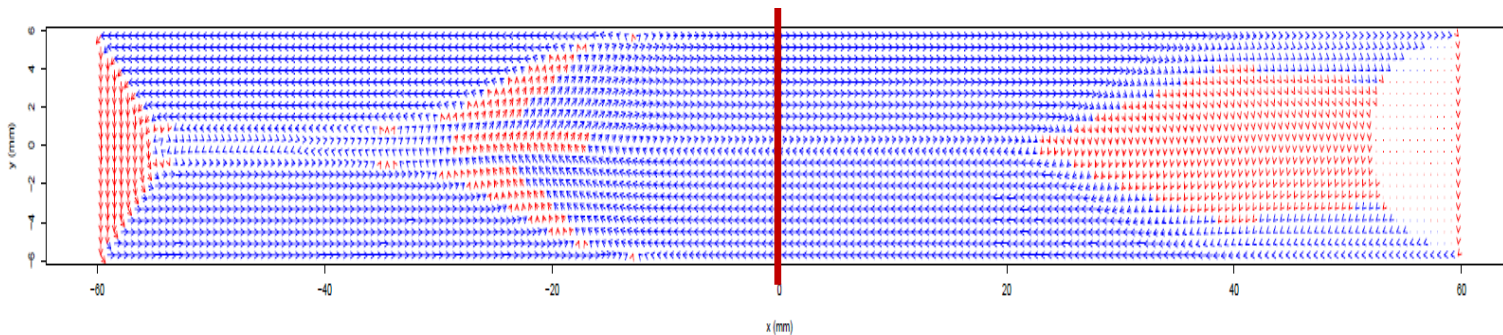
Continuous magnetization



decreasing

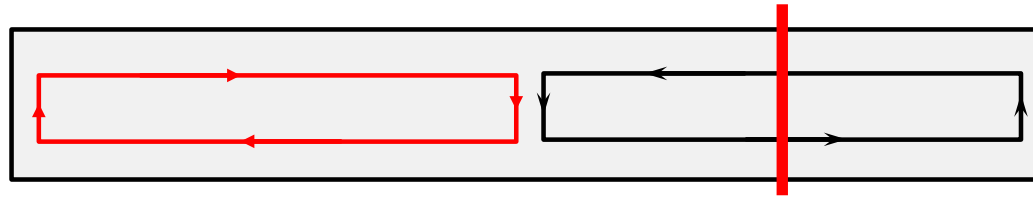
increasing field

Hall Array

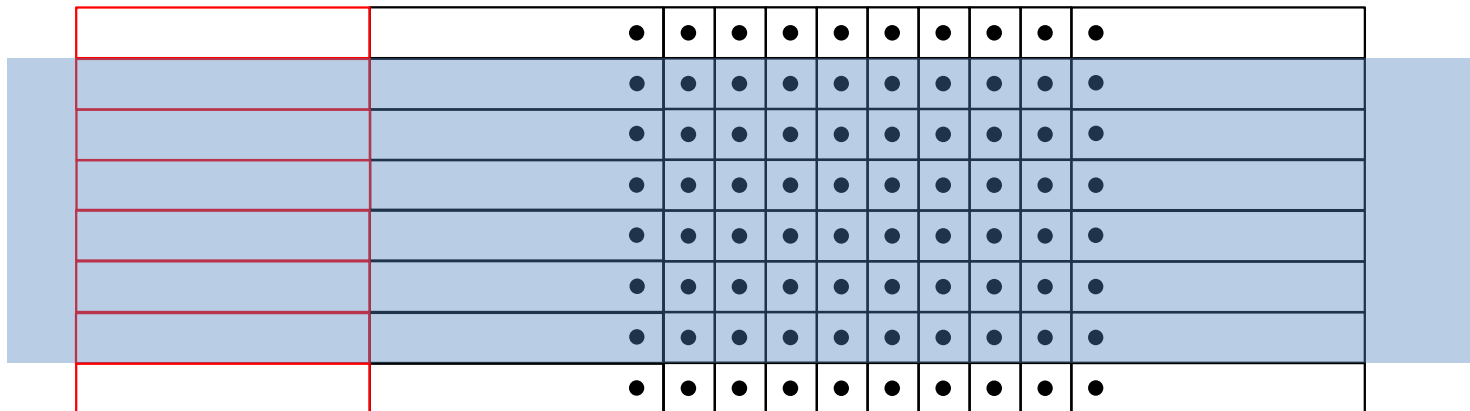


Inversion model

Hall array



Model grid



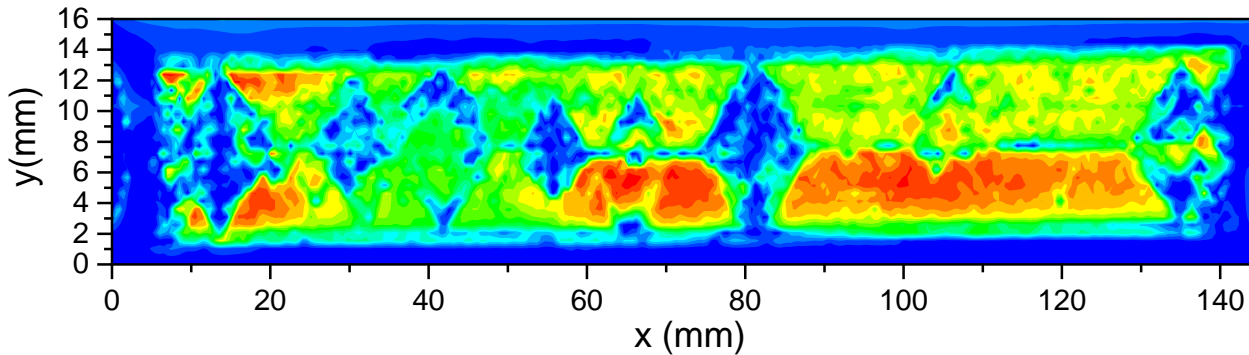
Grid is shifted along the data, only central currents are recorded.

First results

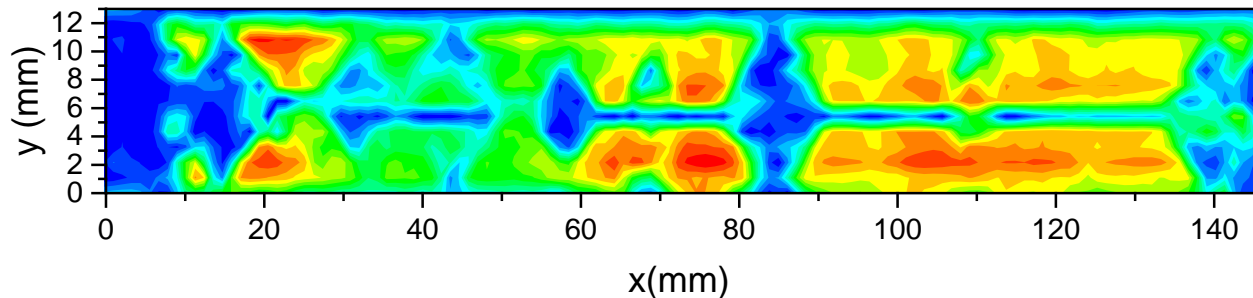


Hall scan 0.5x0.5 mm², 15 μm gap

Local current density along x



Reel-to-reel: 1.1x0.6 mm², 850 μm gap



Good agreement although with different spatial resolution.



CORRECTION FOR MAGNETIC SUBSTRATES



Magnetic substrates



The superconductor magnetizes a magnetic substrate.

→ The field of the substrates adds to the Hall signal.

→ Overestimation of the critical currents.

Iterative approach: Measured local magnetic field map B_H

Inversion (J_c)

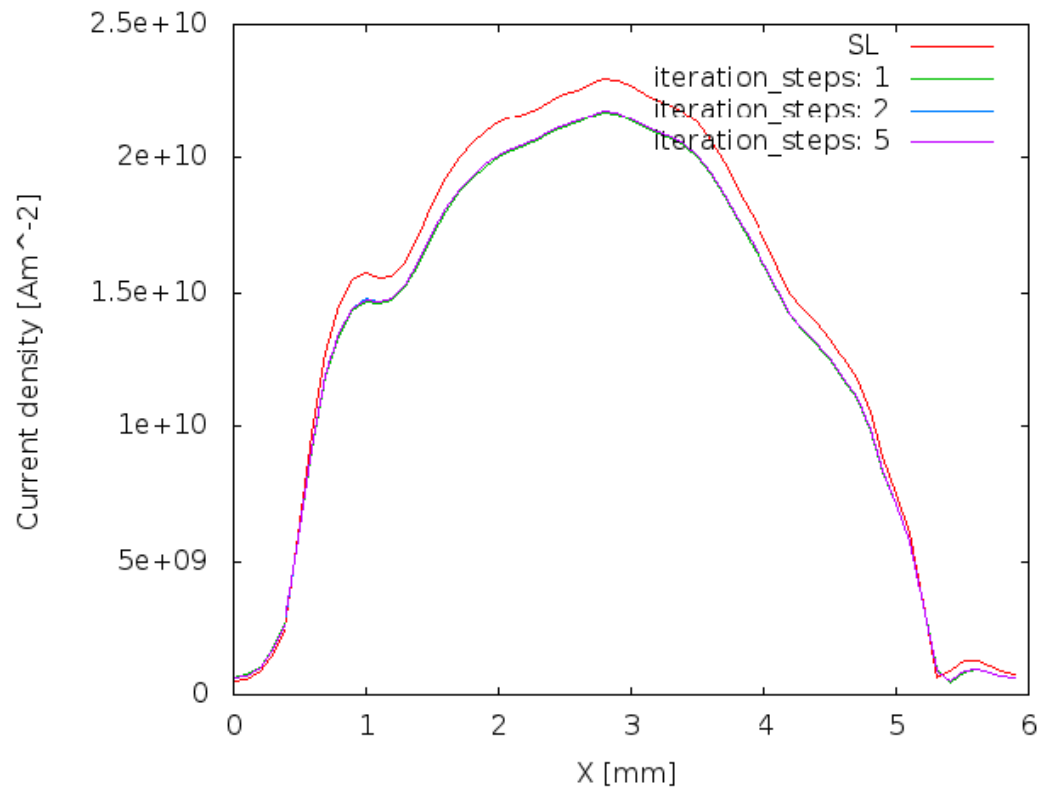
Calculation of the field in the substrate
and according magnetization M

Calculation of the field resulting from
 M at measurement grid

Subtraction from B_H



Fast convergence



Conclusions

- Scanning Hall probe measurements are a powerful tool for the investigation of magnetic granularity
- The measurement grid has to be chosen carefully (gap size, position)
- Discontinuities in the current distribution can be easily “overlooked”.
- The inversion of data obtained from reel-to-reel system needs additional assumptions.
- Non-hysteretic magnetic substrates do not pose a serious problem.

